

# ALTERA<sup>SF</sup>

**MAKE IT  
MEASURE IT**

...on the shop floor



ALTERA SF 20.12.10 with PH10MQ PLUS and TP200

## **Built to thrive in tough conditions**

In today's fast-paced manufacturing environment, precision cannot wait for lab reports. That is why ALTERA SF is engineered to deliver lab-grade accuracy directly on the shop floor, where production happens.

**Contact us to book your demonstration**

[www.LKmetrology.com](http://www.LKmetrology.com)

# ALTERA<sup>SF</sup>

ALTERA SF withstands temperature shifts, vibrations, dust, grime and the daily demands of a production setting. By eliminating the delays of off-floor inspection, ALTERA SF empowers quality teams to detect issues early, improve process control, and keep production running smoothly without compromising throughput. To ensure consistent accuracy, reliability, safety and user-friendly operation, ALTERA SF incorporates a range of advanced features tailored to maintain performance and integrate seamlessly into manufacturing workflows.

## Probe heads

|                  | PH10MQ PLUS                                                                       | REVO 2                                                                            |
|------------------|-----------------------------------------------------------------------------------|-----------------------------------------------------------------------------------|
|                  |  |  |
| Head Type        | Indexing Head                                                                     | 5-axis                                                                            |
| Head Positions   | 720                                                                               | Infinite                                                                          |
| Angular Tilt     | 0 to +105°<br>in 7,5° steps                                                       | -100° to 120°                                                                     |
| Angular Rotation | 0 to +180°<br>in 7,5° steps                                                       | Continuous                                                                        |
| Touch Probe      | TP200                                                                             | -                                                                                 |
| Scanning Probe   | SP25M                                                                             | RSP2, RSP3                                                                        |
| Laser Scanner    | SLK25, LC15DX,<br>L100NX, XC65DX                                                  | -                                                                                 |

## Model Sizes

|         |          |          |          |
|---------|----------|----------|----------|
| 10.10.8 | 15.12.10 | 20.15.12 | 30.15.15 |
| 15.10.8 | 20.12.10 | 25.15.12 | 40.15.15 |

(Measure volume = xxxx00mm)

## Performance

|                     |                              |
|---------------------|------------------------------|
| Volumetric Accuracy | from 1.5 µm +L/375           |
| Repeatability       | from 1.5 µm                  |
| Probing Accuracy    | from 1.4 µm                  |
| Velocity            | from 830 mm/s                |
| Acceleration        | from 2,815 mm/s <sup>2</sup> |



ALTERA SF 15.10.8 with PH10MQ Plus and TP200



**LK Metrology's ceramic technology CMM is guaranteed to maintain its original specification for a period of 10 years\***

\*Conditions apply, see LK Metrology website for full details.



### ✓ Ingress Protection

Guideways protected from contamination, accidental damage and thermal influences.



### ✓ Air Wash System

Avoids temperature imbalances under the CMM table, ensuring stability even in uncontrolled environments.



### ✓ 360° Status Light

Full visibility of the CMM operational status including run, idle, and error conditions.



### ✓ Intelligent AVM

Maintains CMM performance in environments with low-level vibration, such as workshops.